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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	196
Number of Logic Elements/Cells	466
Total RAM Bits	6272
Number of I/O	77
Number of Gates	10000
Voltage - Supply	3V ~ 3.6V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcs10xl-4vq100c

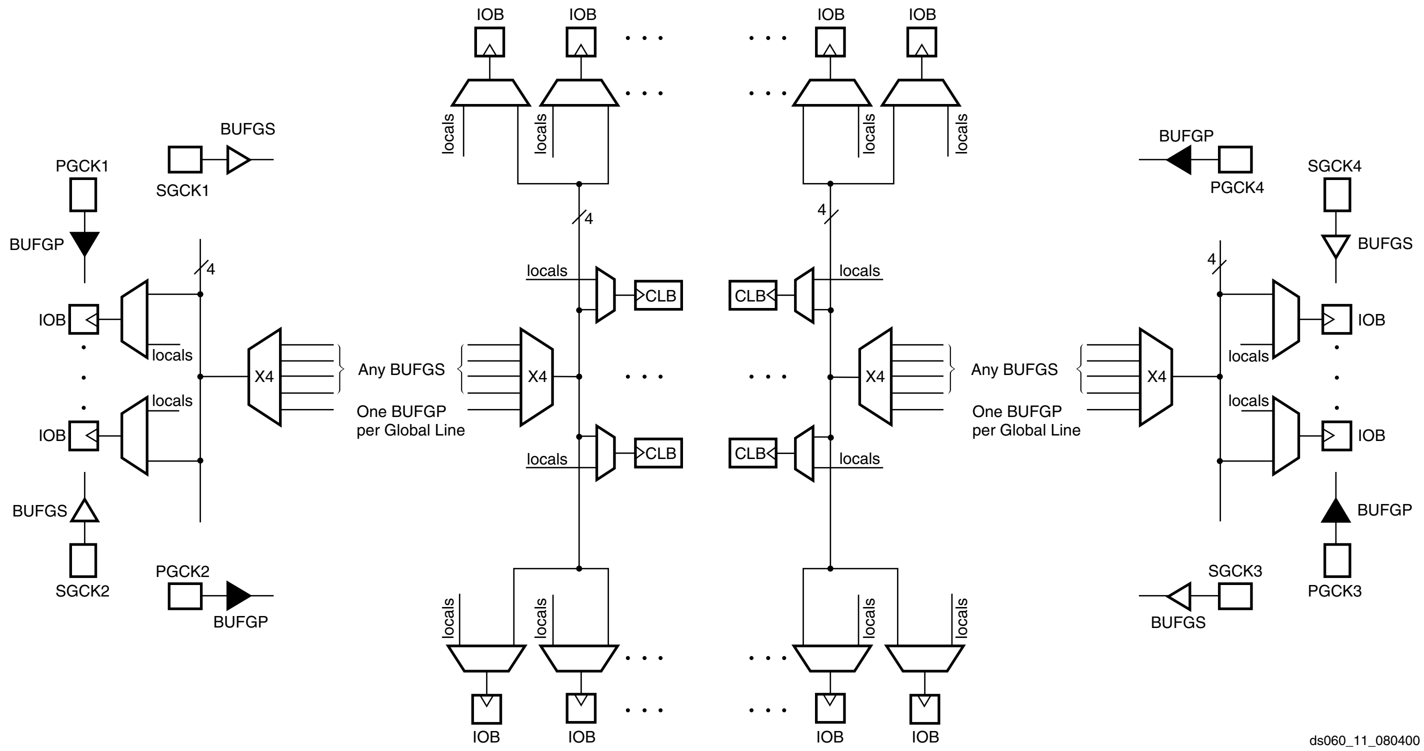


Figure 11: **5V Spartan Family Global Net Distribution**

The four Primary Global buffers offer the shortest delay and negligible skew. Four Secondary Global buffers have slightly longer delay and slightly more skew due to potentially heavier loading, but offer greater flexibility when used to drive non-clock CLB inputs. The eight Global Low-Skew buffers in the Spartan-XL devices combine short delay, negligible skew, and flexibility.

The Primary Global buffers must be driven by the semi-dedicated pads (PGCK1-4). The Secondary Global buffers can be sourced by either semi-dedicated pads (SGCK1-4) or internal nets. Each corner of the device has one Primary buffer and one Secondary buffer. The Spartan-XL family has eight global low-skew buffers, two in each corner. All can be sourced by either semi-dedicated pads (GCK1-8) or internal nets.

Using the library symbol called BUFG results in the software choosing the appropriate clock buffer, based on the timing requirements of the design. A global buffer should be specified for all timing-sensitive global signal distribution. To use a global buffer, place a BUFGP (primary buffer), BUFGS (secondary buffer), BUFGLS (Spartan-XL family global low-skew buffer), or BUFG (any buffer type) element in a schematic or in HDL code.

Advanced Features Description

Distributed RAM

Optional modes for each CLB allow the function generators (F-LUT and G-LUT) to be used as Random Access Memory (RAM).

Read and write operations are significantly faster for this on-chip RAM than for off-chip implementations. This speed advantage is due to the relatively short signal propagation delays within the FPGA.

Memory Configuration Overview

There are two available memory configuration modes: single-port RAM and dual-port RAM. For both these modes, write operations are synchronous (edge-triggered), while read operations are asynchronous. In the single-port mode, a single CLB can be configured as either a 16 x 1, (16 x 1) x 2, or 32 x 1 RAM array. In the dual-port mode, a single CLB can be configured only as one 16 x 1 RAM array. The different CLB memory configurations are summarized in Table 8. Any of these possibilities can be individually programmed into a Spartan/XL FPGA CLB.

Table 8: **CLB Memory Configurations**

Mode	16 x 1	(16 x 1) x 2	32 x 1
Single-Port	√	√	√
Dual-Port	√	–	–

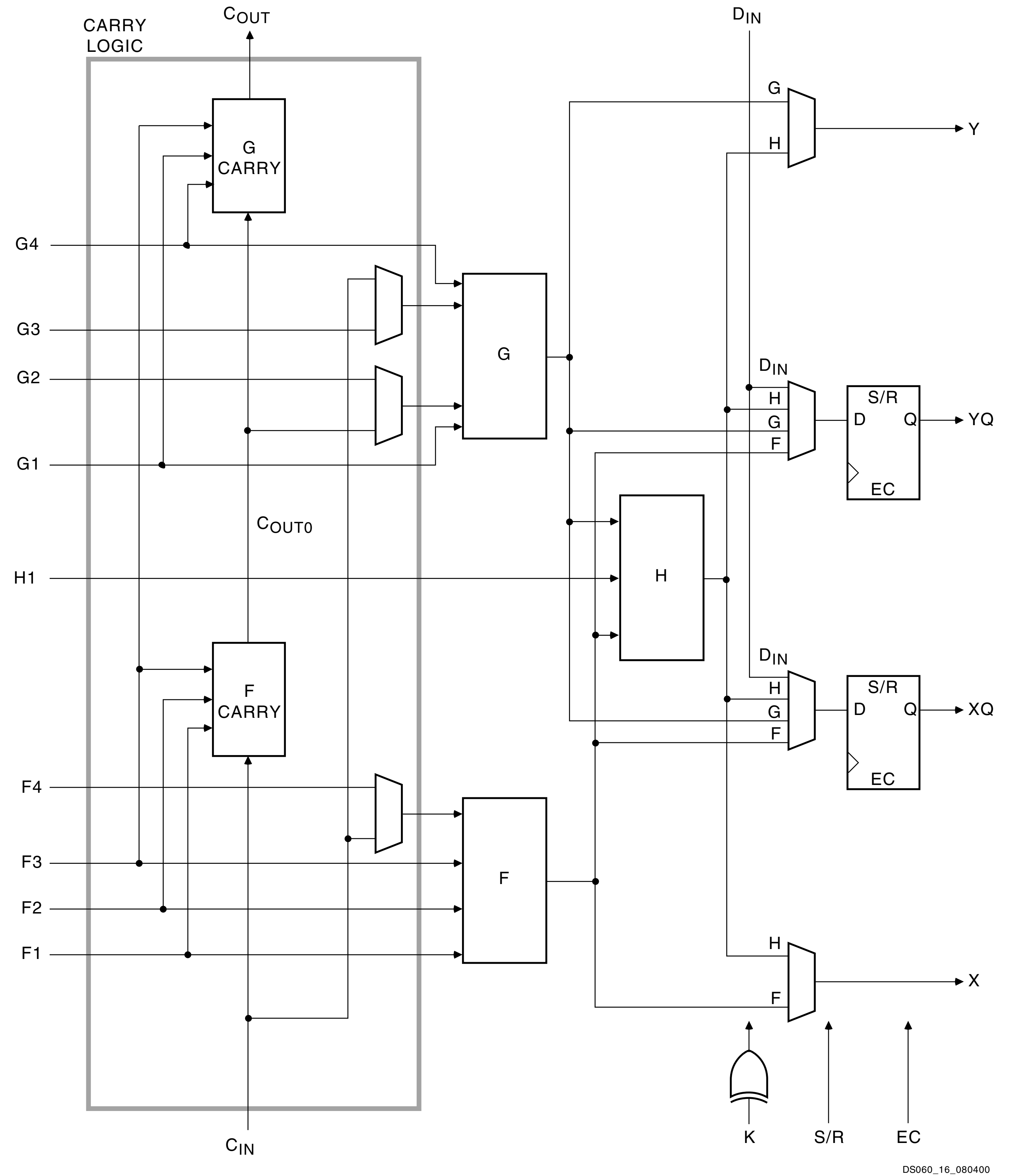


Figure 16: **Fast Carry Logic in Spartan/XL CLB**

Figure 20 is a diagram of the Spartan/XL FPGA boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

Spartan/XL devices can also be configured through the boundary scan logic. See **Configuration Through the Boundary Scan Pins**, page 37.

Data Registers

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out and 3-state Control. Non-IOB pins have appropriate partial bit population for In or Out only. PROGRAM, CCLK and DONE are not included in the boundary scan register. Each EXTEST CAPTURE-DR state captures all In, Out, and 3-state pins.

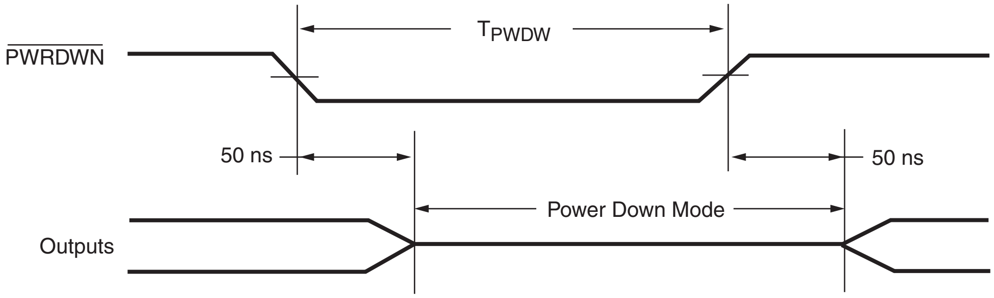
The data register also includes the following non-pin bits: TDO.T, and TDO.O, which are always bits 0 and 1 of the data register, respectively, and BSCANT.UPD, which is always the last bit of the data register. These three boundary scan bits are special-purpose Xilinx test signals.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA provides two additional data registers that can be specified using the BSCAN macro. The FPGA provides two user pins (BSCAN.SEL1 and BSCAN.SEL2) which are the decodes of two user instructions. For these instructions, two corresponding pins (BSCAN.TDO1 and BSCAN.TDO2) allow user scan data to be shifted out on TDO. The data register clock (BSCAN.DRCK) is available for control of test logic which the user may wish to implement with CLBs. The NAND of TCK and RUN-TEST-IDLE is also provided (BSCAN.IDLE).

Instruction Set

The Spartan/XL FPGA boundary scan instruction set also includes instructions to configure the device and read back the configuration data. The instruction set is coded as shown in Table 12.



Description	Symbol	Min
Power Down Time	T_{PWD}	50 ns
Power Down Pulse Width	T_{PWDW}	50 ns

DS060_23_041901

Figure 23: **$\overline{\text{PWRDWN}}$ Pulse Timing**

Power-down retains the configuration, but loses all data stored in the device flip-flops. All inputs are interpreted as Low, but the internal combinatorial logic is fully functional. Make sure that the combination of all inputs Low and all flip-flops set or reset in your design will not generate internal oscillations, or create permanent bus contention by activating internal bus drivers with conflicting data onto the same long line.

During configuration, the $\overline{\text{PWRDWN}}$ pin must be High. If the Power Down state is entered before or during configuration, the device will restart configuration once the $\overline{\text{PWRDWN}}$ signal is removed. Note that the configuration pins are affected by Power Down and may not reflect their normal function. If there is an external pull-up resistor on the DONE pin, it will be High during Power Down even if the device is not yet configured. Similarly, if $\overline{\text{PWRDWN}}$ is asserted before configuration is completed, the $\overline{\text{INIT}}$ pin will not indicate status information.

Note that the $\overline{\text{PWRDWN}}$ pin is not part of the Boundary Scan chain. Therefore, the Spartan-XL family has a separate set of BSDL files than the 5V Spartan family. Boundary scan logic is not usable during Power Down.

Configuration and Test

Configuration is the process of loading design-specific programming data into one or more FPGAs to define the functional operation of the internal blocks and their interconnections. This is somewhat like loading the command registers of a programmable peripheral chip. Spartan/XL devices use several hundred bits of configuration data per CLB and its associated interconnects. Each configuration bit defines the state of a static memory cell that controls either a function look-up table bit, a multiplexer input, or an interconnect pass transistor. The Xilinx development system translates the design into a netlist file. It automatically partitions, places and routes the logic and generates the configuration data in PROM format.

Configuration Mode Control

5V Spartan devices have two configuration modes.

- MODE = 1 sets Slave Serial mode
- MODE = 0 sets Master Serial mode

3V Spartan-XL devices have three configuration modes.

- M1/M0 = 11 sets Slave Serial mode
- M1/M0 = 10 sets Master Serial mode
- M1/M0 = 0X sets Express mode

In addition to these modes, the device can be configured through the Boundary Scan logic (See "Configuration Through the Boundary Scan Pins" on page 37.).

The Mode pins are sampled prior to starting configuration to determine the configuration mode. After configuration, these pin are unused. The Mode pins have a weak pull-up resistor turned on during configuration. With the Mode pins High, Slave Serial mode is selected, which is the most popular configuration mode. Therefore, for the most common configuration mode, the Mode pins can be left unconnected. If the Master Serial mode is desired, the MODE/M0 pin should be connected directly to GND, or through a pull-down resistor of 1 KΩ or less.

During configuration, some of the I/O pins are used temporarily for the configuration process. All pins used during configuration are shown in Table 14 and Table 15.

Table 14: **Pin Functions During Configuration (Spartan Family Only)**

Configuration Mode (MODE Pin)		User Operation
Slave Serial (High)	**Master Serial (Low)**	
MODE (I)	MODE (I)	MODE
HDC (High)	HDC (High)	I/O
$\overline{\text{LDC}}$ (Low)	$\overline{\text{LDC}}$ (Low)	I/O
$\overline{\text{INIT}}$	$\overline{\text{INIT}}$	I/O
DONE	DONE	DONE
$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$
CCLK (I)	CCLK (O)	CCLK (I)
DIN (I)	DIN (I)	I/O
DOUT	DOUT	SGCK4-I/O
TDI	TDI	TDI-I/O
TCK	TCK	TCK-I/O
TMS	TMS	TMS-I/O
TDO	TDO	TDO-(O)
		ALL OTHERS

Notes:
1. A shaded table cell represents the internal pull-up used before and during configuration.
2. (I) represents an input; (O) represents an output.
3. $\overline{\text{INIT}}$ is an open-drain output during configuration.

Table 15: **Pin Functions During Configuration (Spartan-XL Family Only)**

CONFIGURATION MODE <M1:M0>			User Operation
Slave Serial [1:1]	**Master Serial [1:0]**	**Express [0:X]**	
M1 (High) (I)	M1 (High) (I)	M1(Low) (I)	M1
M0 (High) (I)	M0 (Low) (I)	M0 (I)	M0
HDC (High)	HDC (High)	HDC (High)	I/O
$\overline{\text{LDC}}$ (Low)	$\overline{\text{LDC}}$ (Low)	$\overline{\text{LDC}}$ (Low)	I/O
$\overline{\text{INIT}}$	$\overline{\text{INIT}}$	$\overline{\text{INIT}}$	I/O
DONE	DONE	DONE	DONE
$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$
CCLK (I)	CCLK (O)	CCLK (I)	CCLK (I)
		DATA 7 (I)	I/O
		DATA 6 (I)	I/O
		DATA 5 (I)	I/O
		DATA 4 (I)	I/O
		DATA 3 (I)	I/O
		DATA 2 (I)	I/O
		DATA 1 (I)	I/O
DIN (I)	DIN (I)	DATA 0 (I)	I/O
DOUT	DOUT	DOUT	GCK6-I/O
TDI	TDI	TDI	TDI-I/O
TCK	TCK	TCK	TCK-I/O
TMS	TMS	TMS	TMS-I/O
TDO	TDO	TDO	TDO-(O)
		CS1	I/O
			ALL OTHERS

Notes:
1. A shaded table cell represents the internal pull-up used before and during configuration.
2. (I) represents an input; (O) represents an output.
3. $\overline{\text{INIT}}$ is an open-drain output during configuration.

Table 16: **Spartan/XL Data Stream Formats**

Data Type	Serial Modes (D0...)	Express Mode (D0-D7) (Spartan-XL only)
Fill Byte	11111111b	FFFFh
Preamble Code	0010b	11110010b
Length Count	COUNT[23:0]	COUNT[23:0][(1)]
Fill Bits	1111b	-
Field Check Code	-	11010010b
Start Field	0b	11111110b[(2)]
Data Frame	DATA[n–1:0]	DATA[n–1:0]
CRC or Constant Field Check	xxxx (CRC) or 0110b	11010010b
Extend Write Cycle	-	FFD2FFFFFFh
Postamble	01111111b	-
Start-Up Bytes[(3)]	FFh	FFFFFFFFFFFFFFh

Legend:

Unshaded	Once per bitstream
Light	Once per data frame
Dark	Once per device

Notes:
1. Not used by configuration logic.
2. 11111111b for XCS40XL only.
3. Development system may add more start-up bytes.

A selection of CRC or non-CRC error checking is allowed by the bitstream generation software. The Spartan-XL family Express mode only supports non-CRC error checking. The non-CRC error checking tests for a designated end-of-frame field for each frame. For CRC error checking, the software calculates a running CRC and inserts a unique four-bit partial check at the end of each frame. The 11-bit CRC check of the last frame of an FPGA includes the last seven data bits.

Detection of an error results in the suspension of data loading before DONE goes High, and the pulling down of the $\overline{\text{INIT}}$ pin. In Master serial mode, CCLK continues to operate externally. The user must detect $\overline{\text{INIT}}$ and initialize a new configuration by pulsing the $\overline{\text{PROGRAM}}$ pin Low or cycling V_{CC}.

Cyclic Redundancy Check (CRC) for Configuration and Readback

The Cyclic Redundancy Check is a method of error detection in data transmission applications. Generally, the transmitting system performs a calculation on the serial bitstream. The result of this calculation is tagged onto the data stream as additional check bits. The receiving system performs an identical calculation on the bitstream and compares the result with the received checksum.

Each data frame of the configuration bitstream has four error bits at the end, as shown in Table 16. If a frame data error is detected during the loading of the FPGA, the configuration process with a potentially corrupted bitstream is terminated. The FPGA pulls the $\overline{\text{INIT}}$ pin Low and goes into a Wait state.

Table 17: **Spartan/XL Program Data**

Device	XCS05		XCS10		XCS20		XCS30		XCS40	
Max System Gates	5,000		10,000		20,000		30,000		40,000	
CLBs (Row x Col.)	100 (10 x 10)		196 (14 x 14)		400 (20 x 20)		576 (24 x 24)		784 (28 x 28)	
IOBs	80		112		160		192		205(4)	
Part Number	XCS05	XCS05XL	XCS10	XCS10XL	XCS20	XCS20XL	XCS30	XCS30XL	XCS40	XCS40XL
Supply Voltage	5V	3.3V	5V	3.3V	5V	3.3V	5V	3.3V	5V	3.3V
Bits per Frame	126	127	166	167	226	227	266	267	306	307
Frames	428	429	572	573	788	789	932	933	1,076	1,077
Program Data	53,936	54,491	94,960	95,699	178,096	179,111	247,920	249,119	329,264	330,647
PROM Size (bits)	53,984	54,544	95,008	95,752	178,144	179,160	247,968	249,168	329,312	330,696
Express Mode PROM Size (bits)	-	79,072	-	128,488	-	221,056	-	298,696	-	387,856

Notes:
1. Bits per Frame = (10 x number of rows) + 7 for the top + 13 for the bottom + 1 + 1 start bit + 4 error check bits (+1 for Spartan-XL device)
   Number of Frames = (36 x number of columns) + 26 for the left edge + 41 for the right edge + 1 (+ 1 for Spartan-XL device)
   Program Data = (Bits per Frame x Number of Frames) + 8 postamble bits
   PROM Size = Program Data + 40 (header) + 8, rounded up to the nearest byte
2. The user can add more "1" bits as leading dummy bits in the header, or, if CRC = off, as trailing dummy bits at the end of any frame, following the four error check bits. However, the Length Count value **must** be adjusted for all such extra "one" bits, even for extra leading ones at the beginning of the header.
3. Express mode adds 57 (XCS05XL, XCS10XL), or 53 (XCS20XL, XCS30XL, XCS40XL) bits per frame, + additional start-up bits.
4. XCS40XL provided 224 max I/O in CS280 package discontinued by PDN2004-01.

During Readback, 11 bits of the 16-bit checksum are added to the end of the Readback data stream. The checksum is computed using the CRC-16 CCITT polynomial, as shown in Figure 29. The checksum consists of the 11 most significant bits of the 16-bit code. A change in the checksum indicates a change in the Readback bitstream. A comparison to a previous checksum is meaningful only if the readback data is independent of the current device state. CLB outputs should not be included (Readback Capture option not used), and if RAM is present, the RAM content must be unchanged.

Statistically, one error out of 2048 might go undetected.

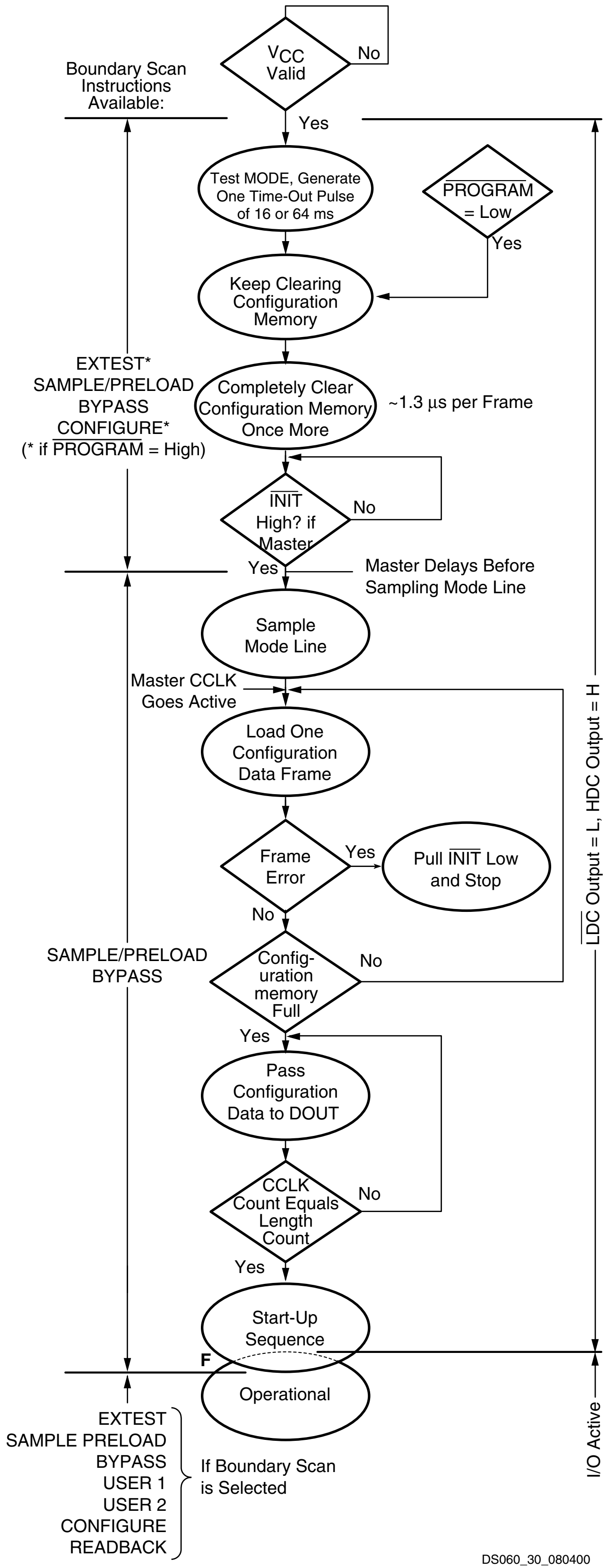


Figure 30: **Power-up Configuration Sequence**

Configuration

The 0010 preamble code indicates that the following 24 bits represent the length count for serial modes. The length count is the total number of configuration clocks needed to load the complete configuration data. (Four additional configuration clocks are required to complete the configuration process, as discussed below.) After the preamble and the length count have been passed through to any device in the daisy chain, its DOUT is held High to prevent frame start bits from reaching any daisy-chained devices. In Spartan-XL family Express mode, the length count bits are ignored, and DOUT is held Low, to disable the next device in the pseudo daisy chain.

A specific configuration bit, early in the first frame of a master device, controls the configuration-clock rate and can increase it by a factor of eight. Therefore, if a fast configuration clock is selected by the bitstream, the slower clock rate is used until this configuration bit is detected.

Each frame has a start field followed by the frame-configuration data bits and a frame error field. If a frame data error is detected, the FPGA halts loading, and signals the error by pulling the open-drain INIT pin Low. After all configuration frames have been loaded into an FPGA using a serial mode, DOUT again follows the input data so that the remaining data is passed on to the next device. In Spartan-XL family Express mode, when the first device is fully programmed, DOUT goes High to enable the next device in the chain.

Delaying Configuration After Power-Up

There are two methods of delaying configuration after power-up: put a logic Low on the PROGRAM input, or pull the bidirectional INIT pin Low, using an open-collector (open-drain) driver. (See Figure 30.)

A Low on the PROGRAM input is the more radical approach, and is recommended when the power-supply rise time is excessive or poorly defined. As long as PROGRAM is Low, the FPGA keeps clearing its configuration memory. When PROGRAM goes High, the configuration memory is cleared one more time, followed by the beginning of configuration, provided the INIT input is not externally held Low. Note that a Low on the PROGRAM input automatically forces a Low on the INIT output. The Spartan/XL FPGA PROGRAM pin has a permanent weak pull-up.

Avoid holding PROGRAM Low for more than 500 µs. The 500 µs maximum limit is only a recommendation, not a requirement. The only effect of holding PROGRAM Low for more than 500 µs is an increase in current, measured at about 40 mA in the XCS40XL. This increased current cannot damage the device. This applies only during reconfiguration, not during power-up. The INIT pin can also be held Low to delay reconfiguration, and the same characteristics apply as for the PROGRAM pin.

Using an open-collector or open-drain driver to hold INIT Low before the beginning of configuration causes the FPGA

Spartan Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan devices and are expressed in nanoseconds unless otherwise noted.

Symbol	Single Port RAM	Size(1)	Speed Grade -4 Min	-4 Max	-3 Min	-3 Max	Units
Write Operation							
T_{WCS}	Address write cycle time (clock K period)	16x2	8.0	-	11.6	-	ns
T_{WCTS}		32x1	8.0	-	11.6	-	ns
T_{WPS}	Clock K pulse width (active edge)	16x2	4.0	-	5.8	-	ns
T_{WPTS}		32x1	4.0	-	5.8	-	ns
T_{ASS}	Address setup time before clock K	16x2	1.5	-	2.0	-	ns
T_{ASTS}		32x1	1.5	-	2.0	-	ns
T_{AHS}	Address hold time after clock K	16x2	0.0	-	0.0	-	ns
T_{AHTS}		32x1	0.0	-	0.0	-	ns
T_{DSS}	DIN setup time before clock K	16x2	1.5	-	2.7	-	ns
T_{DSTS}		32x1	1.5	-	1.7	-	ns
T_{DHS}	DIN hold time after clock K	16x2	0.0	-	0.0	-	ns
T_{DHTS}		32x1	0.0	-	0.0	-	ns
T_{WSS}	WE setup time before clock K	16x2	1.5	-	1.6	-	ns
T_{WSTS}		32x1	1.5	-	1.6	-	ns
T_{WHS}	WE hold time after clock K	16x2	0.0	-	0.0	-	ns
T_{WHTS}		32x1	0.0	-	0.0	-	ns
T_{WOS}	Data valid after clock K	16x2	-	6.5	-	7.9	ns
T_{WOTS}		32x1	-	7.0	-	9.3	ns
Read Operation							
T_{RC}	Address read cycle time	16x2	2.6	-	2.6	-	ns
T_{RCT}		32x1	3.8	-	3.8	-	ns
T_{ILO}	Data valid after address change (no Write Enable)	16x2	-	1.2	-	1.6	ns
T_{IHO}		32x1	-	2.0	-	2.7	ns
T_{ICK}	Address setup time before clock K	16x2	1.8	-	2.4	-	ns
T_{IHCK}		32x1	2.9	-	3.9	-	ns

Notes:
1. Timing for 16 x 1 RAM option is identical to 16 x 2 RAM timing.

Spartan Family Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case operating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading. For more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report.

Spartan Family Output Flip-Flop, Clock-to-Out

Symbol	Description	Device	Speed Grade -4 Max	Speed Grade -3 Max	Units
Global Primary Clock to TTL Output using OFF					
T_{ICKOF}	Fast	XCS05	5.3	8.7	ns
		XCS10	5.7	9.1	ns
		XCS20	6.1	9.3	ns
		XCS30	6.5	9.4	ns
		XCS40	6.8	10.2	ns
T_{ICKO}	Slew-rate limited	XCS05	9.0	11.5	ns
		XCS10	9.4	12.0	ns
		XCS20	9.8	12.2	ns
		XCS30	10.2	12.8	ns
		XCS40	10.5	12.8	ns
Global Secondary Clock to TTL Output using OFF					
T_{ICKSOF}	Fast	XCS05	5.8	9.2	ns
		XCS10	6.2	9.6	ns
		XCS20	6.6	9.8	ns
		XCS30	7.0	9.9	ns
		XCS40	7.3	10.7	ns
T_{ICKSO}	Slew-rate limited	XCS05	9.5	12.0	ns
		XCS10	9.9	12.5	ns
		XCS20	10.3	12.7	ns
		XCS30	10.7	13.2	ns
		XCS40	11.0	14.3	ns
Delay Adder for CMOS Outputs Option					
T_{CMOSOF}	Fast	All devices	0.8	1.0	ns
T_{CMOSO}	Slew-rate limited	All devices	1.5	2.0	ns

Notes:
1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column,and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at ~50% V_{CC} threshold with 50 pF external capacitive load. For different loads, see Figure 34.
3. OFF = Output Flip-Flop

Spartan Family IOB Output Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values are expressed in nanoseconds unless otherwise noted.

Symbol	Description	Device	Speed Grade				Units
			-4		-3		
			Min	Max	Min	Max	
Clocks							
T_{CH}	Clock High	All devices	3.0	-	4.0	-	ns
T_{CL}	Clock Low	All devices	3.0	-	4.0	-	ns
Propagation Delays - TTL Outputs(1,2)							
T_{OKPOF}	Clock (OK) to Pad, fast	All devices	-	3.3	-	4.5	ns
T_{OKPOS}	Clock (OK to Pad, slew-rate limited	All devices	-	6.9	-	7.0	ns
T_{OPF}	Output (O) to Pad, fast	All devices	-	3.6	-	4.8	ns
T_{OPS}	Output (O) to Pad, slew-rate limited	All devices	-	7.2	-	7.3	ns
T_{TSHZ}	3-state to Pad High-Z (slew-rate independent)	All devices	-	3.0	-	3.8	ns
T_{TSONF}	3-state to Pad active and valid, fast	All devices	-	6.0	-	7.3	ns
T_{TSONS}	3-state to Pad active and valid, slew-rate limited	All devices	-	9.6	-	9.8	ns
Setup and Hold Times							
T_{OOK}	Output (O) to clock (OK) setup time	All devices	2.5	-	3.8	-	ns
T_{OKO}	Output (O) to clock (OK) hold time	All devices	0.0	-	0.0	-	ns
T_{ECOK}	Clock Enable (EC) to clock (OK) setup time	All devices	2.0	-	2.7	-	ns
T_{OKEC}	Clock Enable (EC) to clock (OK) hold time	All devices	0.0	-	0.5	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	11.5		13.5		ns
T_{RPO}	Delay from GSR input to any Pad	XCS05	-	12.0	-	15.0	ns
		XCS10	-	12.5	-	15.7	ns
		XCS20	-	13.0	-	16.2	ns
		XCS30	-	13.5	-	16.9	ns
		XCS40	-	14.0	-	17.5	ns

Notes:
1. Delay adder for CMOS Outputs option (with fast slew rate option): for -3 speed grade, add 1.0 ns; for -4 speed grade, add 0.8 ns.
2. Delay adder for CMOS Outputs option (with slow slew rate option): for -3 speed grade, add 2.0 ns; for -4 speed grade, add 1.5 ns.
3. Output timing is measured at ~50% V_{CC} threshold, with 50 pF external capacitive loads including test fixture. Slew-rate limited output rise/fall times are approximately two times longer than fast output rise/fall times.
4. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

Spartan-XL Family DC Characteristics Over Operating Conditions

Symbol	Description		Min	Typ.	Max	Units
V_{OH}	High-level output voltage @ I_{OH} = –4.0 mA, V_{CC} min (LVTTL)		2.4	-	-	V
	High-level output voltage @ I_{OH} = –500 µA, (LVCMOS)		90% V_{CC}	-	-	V
V_{OL}	Low-level output voltage @ I_{OL} = 12.0 mA, V_{CC} min (LVTTL)(1)		-	-	0.4	V
	Low-level output voltage @ I_{OL} = 24.0 mA, V_{CC} min (LVTTL)(2)		-	-	0.4	V
	Low-level output voltage @ I_{OL} = 1500 µA, (LVCMOS)		-	-	10% V_{CC}	V
V_{DR}	Data retention supply voltage (below which configuration data may be lost)		2.5	-	-	V
I_{CCO}	Quiescent FPGA supply current(3,4)	Commercial	-	0.1	2.5	mA
		Industrial	-	0.1	5	mA
I_{CCPD}	Power Down FPGA supply current(3,5)	Commercial	-	0.1	2.5	mA
		Industrial	-	0.1	5	mA
I_L	Input or output leakage current		–10	-	10	µA
C_{IN}	Input capacitance (sample tested)		-	-	10	pF
I_{RPU}	Pad pull-up (when selected) @ V_{IN} = 0V (sample tested)		0.02	-	0.25	mA
I_{RPD}	Pad pull-down (when selected) @ V_{IN} = 3.3V (sample tested)		0.02	-	-	mA

Notes:
1. With up to 64 pins simultaneously sinking 12 mA (default mode).
2. With up to 64 pins simultaneously sinking 24 mA (with 24 mA option selected).
3. With 5V tolerance not selected, no internal oscillators, and the FPGA configured with the Tie option.
4. With no output current loads, no active input resistors, and all package pins at V_{CC} or GND.
5. With $\overline{\text{PWRDWN}}$ active.

Supply Current Requirements During Power-On

Spartan-XL FPGAs require that a minimum supply current I_{CCPO} be provided to the V_{CC} lines for a successful power on. If more current is available, the FPGA can consume more than I_{CCPO} min., though this cannot adversely affect reliability.

A maximum limit for I_{CCPO} is not specified. Be careful when using foldback/crowbar supplies and fuses. It is possible to control the magnitude of I_{CCPO} by limiting the supply current available to the FPGA. A current limit below the trip level will avoid inadvertently activating over-current protection circuits.

Symbol	Description	Min	Max	Units
I_{CCPO}	Total V_{CC} supply current required during power-on	100	-	mA
T_{CCPO}	V_{CC} ramp time(2,3)	-	50	ms

Notes:
1. The I_{CCPO} requirement applies for a brief time (commonly only a few milliseconds) when V_{CC} ramps from 0 to 3.3V.
2. The ramp time is measured from GND to V_{CC} max on a fully loaded board.
3. V_{CC} must not dip in the negative direction during power on.

Spartan-XL Family Global Buffer Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

When fewer vertical clock lines are connected, the clock distribution is faster; when multiple clock lines per column are driven from the same global clock, the delay is longer. For more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade		Units
			-5	-4	
			Max	Max	
T_{GLS}	From pad through buffer, to any clock K	XCS05XL	1.4	1.5	ns
		XCS10XL	1.7	1.8	ns
		XCS20XL	2.0	2.1	ns
		XCS30XL	2.3	2.5	ns
		XCS40XL	2.6	2.8	ns

Spartan-XL Family CLB Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-XL devices and expressed in nanoseconds unless otherwise noted.

Symbol	Description	Speed Grade				Units
		-5		-4		
		Min	Max	Min	Max	
Clocks						
T_{CH}	Clock High time	2.0	-	2.3	-	ns
T_{CL}	Clock Low time	2.0	-	2.3	-	ns
Combinatorial Delays						
T_{ILO}	F/G inputs to X/Y outputs	-	1.0	-	1.1	ns
T_{IHO}	F/G inputs via H to X/Y outputs	-	1.7	-	2.0	ns
T_{ITO}	F/G inputs via transparent latch to Q outputs	-	1.5	-	1.8	ns
T_{HH1O}	C inputs via H1 via H to X/Y outputs	-	1.5	-	1.8	ns
Sequential Delays						
T_{CKO}	Clock K to Flip-Flop or latch outputs Q	-	1.2	-	1.4	ns
Setup Time before Clock K						
T_{ICK}	F/G inputs	0.6	-	0.7	-	ns
T_{IHCK}	F/G inputs via H	1.3	-	1.6	-	ns
Hold Time after Clock K						
	All Hold times, all devices	0.0	-	0.0	-	ns
Set/Reset Direct						
T_{RPW}	Width (High)	2.5	-	2.8	-	ns
T_{RIO}	Delay from C inputs via S/R, going High to Q	-	2.3	-	2.7	ns
Global Set/Reset						
T_{MRW}	Minimum GSR Pulse Width	10.5	-	11.5	-	ns
T_{MRQ}	Delay from GSR input to any Q	See page 60 for T_{RRI} values per device.				
F_{TOG}	Toggle Frequency (MHz) (for export control purposes)	-	250	-	217	MHz

Spartan-XL Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-XL devices and are expressed in nanoseconds unless otherwise noted.

Symbol	Single Port RAM	Size(1)	Speed Grade -5 Min	-5 Max	-4 Min	-4 Max	Units
Write Operation							
T_{WCS}	Address write cycle time (clock K period)	16x2	7.7	-	8.4	-	ns
T_{WCTS}		32x1	7.7	-	8.4	-	ns
T_{WPS}	Clock K pulse width (active edge)	16x2	3.1	-	3.6	-	ns
T_{WPTS}		32x1	3.1	-	3.6	-	ns
T_{ASS}	Address setup time before clock K	16x2	1.3	-	1.5	-	ns
T_{ASTS}		32x1	1.5	-	1.7	-	ns
T_{DSS}	DIN setup time before clock K	16x2	1.5	-	1.7	-	ns
T_{DSTS}		32x1	1.8	-	2.1	-	ns
T_{WSS}	WE setup time before clock K	16x2	1.4	-	1.6	-	ns
T_{WSTS}		32x1	1.3	-	1.5	-	ns
	All hold times after clock K	16x2	0.0	-	0.0	-	ns
T_{WOS}	Data valid after clock K	32x1	-	4.5	-	5.3	ns
T_{WOTS}		16x2	-	5.4	-	6.3	ns
Read Operation							
T_{RC}	Address read cycle time	16x2	2.6	-	3.1	-	ns
T_{RCT}		32x1	3.8	-	5.5	-	ns
T_{ILO}	Data Valid after address change (no Write Enable)	16x2	-	1.0	-	1.1	ns
T_{IHO}		32x1	-	1.7	-	2.0	ns
T_{ICK}	Address setup time before clock K	16x2	0.6	-	0.7	-	ns
T_{IHCK}		32x1	1.3	-	1.6	-	ns

Notes:
1. Timing for 16 x 1 RAM option is identical to 16 x 2 RAM timing.

Pin Descriptions

There are three types of pins in the Spartan/XL devices:

- Permanently dedicated pins
- User I/O pins that can have special functions
- Unrestricted user-programmable I/O pins.

Before and during configuration, all outputs not used for the configuration process are 3-stated with the I/O pull-up resistor network activated. After configuration, if an IOB is unused it is configured as an input with the I/O pull-up resistor network remaining activated.

Any user I/O can be configured to drive the Global Set/Reset net GSR or the global three-state net GTS. See **Global Signals: GSR and GTS**, page 20 for more information.

Device pins for Spartan/XL devices are described in Table 18.

Some Spartan-XL devices are available in Pb-free package options. The Pb-free package options have the same pinouts as the standard package options.

Table 18: **Pin Descriptions**

Pin Name	I/O During Config.	I/O After Config.	Pin Description
Permanently Dedicated Pins			
V_{CC}	X	X	Eight or more (depending on package) connections to the nominal +5V supply voltage (+3.3V for Spartan-XL devices). All must be connected, and each must be decoupled with a 0.01 –0.1 μF capacitor to Ground.
GND	X	X	Eight or more (depending on package type) connections to Ground. All must be connected.
CCLK	I or O	I	During configuration, Configuration Clock (CCLK) is an output in Master mode and is an input in Slave mode. After configuration, CCLK has a weak pull-up resistor and can be selected as the Readback Clock. There is no CCLK High or Low time restriction on Spartan/XL devices, except during Readback. See **Violating the Maximum High and Low Time Specification for the Readback Clock**, page 39 for an explanation of this exception.
DONE	I/O	O	DONE is a bidirectional signal with an optional internal pull-up resistor. As an open-drain output, it indicates the completion of the configuration process. As an input, a Low level on DONE can be configured to delay the global logic initialization and the enabling of outputs. The optional pull-up resistor is selected as an option in the program that creates the configuration bitstream. The resistor is included by default.
$\overline{\text{PROGRAM}}$	I	I	$\overline{\text{PROGRAM}}$ is an active Low input that forces the FPGA to clear its configuration memory. It is used to initiate a configuration cycle. When $\overline{\text{PROGRAM}}$ goes High, the FPGA finishes the current clear cycle and executes another complete clear cycle, before it goes into a WAIT state and releases $\overline{\text{INIT}}$. The $\overline{\text{PROGRAM}}$ pin has a permanent weak pull-up, so it need not be externally pulled up to VCC.
MODE (Spartan) M0, M1 (Spartan-XL)	I	X	The Mode input(s) are sampled after $\overline{\text{INIT}}$ goes High to determine the configuration mode to be used. During configuration, these pins have a weak pull-up resistor. For the most popular configuration mode, Slave Serial, the mode pins can be left unconnected. For Master Serial mode, connect the Mode/M0 pin directly to system ground.

Additional XCS20/XL Package Pins

PQ208					
Not Connected Pins					
P12	P18 (1)	P33 (1)	P39	P65	P71 (1)
P86 (1)	P92	P111	P121(1)	P140(1)	P144
P165	P173(1)	P192(1)	P202	P203	-
9/16/98					

Notes:

1. 5V Spartan family only
2. 3V Spartan-XL family only
3. The “PWRDWN” on the XCS20XL is not part of the Boundary Scan chain. For the XCS20XL, subtract 1 from all Boundary Scan numbers from GCK3 on (247 and higher).
4. CS144 package discontinued by PDN2004-01

XCS30 and XCS30XL Device Pinouts

XCS30/XL Pad Name	VQ100(5)	TQ144	PQ208	PQ240	BG256(5)	CS280(2,5)	Bndry Scan
VCC	P89	P128	P183	P212	VCC(4)	C10	-
I/O	P90	P129	P184	P213	C10	D10	74
I/O	P91	P130	P185	P214	D10	E10	77
I/O	P92	P131	P186	P215	A9	A9	80
I/O	P93	P132	P187	P216	B9	B9	83
I/O	-	-	P188	P217	C9	C9	86
I/O	-	-	P189	P218	D9	D9	89
I/O	P94	P133	P190	P220	A8	A8	92
I/O	P95	P134	P191	P221	B8	B8	95
VCC	-	-	P192	P222	VCC(4)	A7	-
I/O	-	-	-	P223	A6	B7	98
I/O	-	-	-	P224	C7	C7	101
I/O	-	P135	P193	P225	B6	D7	104
I/O	-	P136	P194	P226	A5	A6	107
GND	-	P137	P195	P227	GND(4)	GND(4)	-
I/O	-	-	P196	P228	C6	B6	110
I/O	-	-	P197	P229	B5	C6	113
I/O	-	-	P198	P230	A4	D6	116
I/O	-	-	P199	P231	C5	E6	119
I/O	P96	P138	P200	P232	B4	A5	122
I/O	P97	P139	P201	P233	A3	C5	125
I/O	-	-	P202	P234	D5	B4	128
I/O	-	-	P203	P235	C4	C4	131
I/O	-	P140	P204	P236	B3	A3	134
I/O	-	P141	P205	P237	B2	A2	137
I/O	P98	P142	P206	P238	A2	B3	140
I/O, SGCK1(1), GCK8(2)	P99	P143	P207	P239	C3	B2	143
VCC	P100	P144	P208	P240	VCC(4)	A1	-
GND	P1	P1	P1	P1	GND(4)	GND(4)	-
I/O, PGCK1(1), GCK1(2)	P2	P2	P2	P2	B1	C3	146
I/O	P3	P3	P3	P3	C2	C2	149
I/O	-	P4	P4	P4	D2	B1	152

XCS30 and XCS30XL Device Pinouts *(Continued)*

XCS30/XL Pad Name	VQ100[5]	TQ144	PQ208	PQ240	BG256[5]	CS280[2,5]	Bndry Scan
I/O	-	P5	P5	P5	D3	C1	155
I/O, TDI	P4	P6	P6	P6	E4	D4	158
I/O, TCK	P5	P7	P7	P7	C1	D3	161
I/O	-	-	P8	P8	D1	E2	164
I/O	-	-	P9	P9	E3	E4	167
I/O	-	-	P10	P10	E2	E1	170
I/O	-	-	P11	P11	E1	F5	173
I/O	-	-	P12	P12	F3	F3	176
I/O	-	-	-	P13	F2	F2	179
GND	-	P8	P13	P14	GND[4]	GND[4]	-
I/O	-	P9	P14	P15	G3	F4	182
I/O	-	P10	P15	P16	G2	F1	185
I/O, TMS	P6	P11	P16	P17	G1	G3	188
I/O	P7	P12	P17	P18	H3	G2	191
VCC	-	-	P18	P19	VCC[4]	G1	-
I/O	-	-	-	P20	H2	G4	194
I/O	-	-	-	P21	H1	H1	197
I/O	-	-	P19	P23	J2	H4	200
I/O	-	-	P20	P24	J1	J1	203
I/O	-	P13	P21	P25	K2	J2	206
I/O	P8	P14	P22	P26	K3	J3	209
I/O	P9	P15	P23	P27	K1	J4	212
I/O	P10	P16	P24	P28	L1	K1	215
GND	P11	P17	P25	P29	GND[4]	GND[4]	-
VCC	P12	P18	P26	P30	VCC[4]	K2	-
I/O	P13	P19	P27	P31	L2	K3	218
I/O	P14	P20	P28	P32	L3	K4	221
I/O	P15	P21	P29	P33	L4	K5	224
I/O	-	P22	P30	P34	M1	L1	227
I/O	-	-	P31	P35	M2	L2	230
I/O	-	-	P32	P36	M3	L3	233
I/O	-	-	-	P38	N1	M2	236
I/O	-	-	-	P39	N2	M3	239
VCC	-	-	P33	P40	VCC[4]	M4	-
I/O	P16	P23	P34	P41	P1	N1	242
I/O	P17	P24	P35	P42	P2	N2	245
I/O	-	P25	P36	P43	R1	N3	248
I/O	-	P26	P37	P44	P3	N4	251
GND	-	P27	P38	P45	GND[4]	GND[4]	-
I/O	-	-	-	P46	T1	P1	254
I/O	-	-	P39	P47	R3	P2	257
I/O	-	-	P40	P48	T2	P3	260
I/O	-	-	P41	P49	U1	P4	263
I/O	-	-	P42	P50	T3	P5	266
I/O	-	-	P43	P51	U2	R1	269

XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280(2,5)	Bndry Scan
GND	P25	P29	GND(4)	GND(4)	-
VCC	P26	P30	VCC(4)	VCC(4)	-
I/O	P27	P31	L2	K3	254
I/O	P28	P32	L3	K4	257
I/O	P29	P33	L4	K5	260
I/O	P30	P34	M1	L1	263
I/O	P31	P35	M2	L2	266
I/O	P32	P36	M3	L3	269
I/O	-	-	M4	L4	272
I/O	-	-	-	M1	275
I/O	-	P38	N1	M2	278
I/O	-	P39	N2	M3	281
VCC	P33	P40	VCC(4)	VCC(4)	-
I/O	P34	P41	P1	N1	284
I/O	P35	P42	P2	N2	287
I/O	P36	P43	R1	N3	290
I/O	P37	P44	P3	N4	293
GND	P38	P45	GND(4)	GND(4)	-
I/O	-	P46	T1	P1	296
I/O	P39	P47	R3	P2	299
I/O	P40	P48	T2	P3	302
I/O	P41	P49	U1	P4	305
I/O	P42	P50	T3	P5	308
I/O	P43	P51	U2	R1	311
I/O	-	-	-	R2	314
I/O	-	-	-	R4	317
I/O	P44	P52	V1	T1	320
I/O	P45	P53	T4	T2	323
I/O	P46	P54	U3	T3	326
I/O	P47	P55	V2	U1	329
I/O	P48	P56	W1	V1	332
I/O, SGCK2(1), GCK2 (2)	P49	P57	V3	U2	335
Not Connected(1) M1(2)	P50	P58	W2	V2	338
GND	P51	P59	GND(4)	GND(4)	-
MODE(1), M0(2)	P52	P60	Y1	W1	341
VCC	P53	P61	VCC(4)	VCC(4)	-
Not Connected(1) PWRDWN(2)	P54	P62	W3	V3	342(1)
I/O, PGCK2(1), GCK3(2)	P55	P63	Y2	W2	343 (3)

XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280(2,5)	Bndry Scan
I/O (HDC)	P56	P64	W4	W3	346 (3)
I/O	P57	P65	V4	T4	349 (3)
I/O	P58	P66	U5	U4	352 (3)
I/O	P59	P67	Y3	V4	355 (3)
I/O (LDC)	P60	P68	Y4	W4	358 (3)
I/O	-	-	-	R5	361 (3)
I/O	-	-	-	U5	364 (3)
I/O	P61	P69	V5	T5	367 (3)
I/O	P62	P70	W5	W5	370 (3)
I/O	P63	P71	Y5	R6	373 (3)
I/O	P64	P72	V6	U6	376 (3)
I/O	P65	P73	W6	V6	379 (3)
I/O	-	P74	Y6	T6	382 (3)
GND	P66	P75	GND(4)	GND(4)	-
I/O	P67	P76	W7	W6	385 (3)
I/O	P68	P77	Y7	U7	388 (3)
I/O	P69	P78	V8	V7	391 (3)
I/O	P70	P79	W8	W7	394 (3)
VCC	P71	P80	VCC(4)	VCC(4)	-
I/O	P72	P81	Y8	W8	397 (3)
I/O	P73	P82	U9	U8	400 (3)
I/O	-	-	V9	V8	403 (3)
I/O	-	-	W9	T8	406 (3)
I/O	-	P84	Y9	W9	409 (3)
I/O	-	P85	W10	V9	412 (3)
I/O	P74	P86	V10	U9	415 (3)
I/O	P75	P87	Y10	T9	418 (3)
I/O	P76	P88	Y11	W10	421 (3)
I/O (INIT)	P77	P89	W11	V10	424 (3)
VCC	P78	P90	VCC(4)	VCC(4)	VCC(4)
GND	P79	P91	GND(4)	GND(4)	-
I/O	P80	P92	V11	T10	427 (3)
I/O	P81	P93	U11	R10	430 (3)
I/O	P82	P94	Y12	W11	433 (3)
I/O	P83	P95	W12	V11	436 (3)
I/O	P84	P96	V12	U11	439 (3)
I/O	P85	P97	U12	T11	442 (3)
I/O	-	-	Y13	W12	445 (3)
I/O	-	-	W13	V12	448 (3)
I/O	-	P99	V13	U12	451 (3)
I/O	-	P100	Y14	T12	454 (3)
VCC	P86	P101	VCC(4)	VCC(4)	-
I/O	P87	P102	Y15	V13	457 (3)
I/O	P88	P103	V14	U13	460 (3)
I/O	P89	P104	W15	T13	463 (3)

XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280[2,5]	Bndry Scan
I/O	P90	P105	Y16	W14	466 [3]
GND	P91	P106	GND[4]	GND[4]	-
I/O	-	P107	V15	V14	469 [3]
I/O	P92	P108	W16	U14	472 [3]
I/O	P93	P109	Y17	T14	475 [3]
I/O	P94	P110	V16	R14	478 [3]
I/O	P95	P111	W17	W15	481 [3]
I/O	P96	P112	Y18	U15	484 [3]
I/O	-	-	-	T15	487 [3]
I/O	-	-	-	W16	490 [3]
I/O	P97	P113	U16	V16	493 [3]
I/O	P98	P114	V17	U16	496 [3]
I/O	P99	P115	W18	W17	499 [3]
I/O	P100	P116	Y19	W18	502 [3]
I/O	P101	P117	V18	V17	505 [3]
I/O, SGCK3[1], GCK4[2]	P102	P118	W19	V18	508 [3]
GND	P103	P119	GND[4]	GND[4]	-
DONE	P104	P120	Y20	W19	-
VCC	P105	P121	VCC[4]	VCC[4]	-
$\overline{\text{PROGRAM}}$	P106	P122	V19	U18	-
I/O (D7[2])	P107	P123	U19	V19	511 [3]
I/O, PGCK3[1], GCK5[2]	P108	P124	U18	U19	514 [3]
I/O	P109	P125	T17	T16	517 [3]
I/O	P110	P126	V20	T17	520 [3]
I/O	-	P127	U20	T18	523 [3]
I/O	P111	P128	T18	T19	526 [3]
I/O	-	-	-	R15	529 [3]
I/O	-	-	-	R17	523 [3]
I/O (D6[2])	P112	P129	T19	R16	535 [3]
I/O	P113	P130	T20	R19	538 [3]
I/O	P114	P131	R18	P15	541 [3]
I/O	P115	P132	R19	P17	544 [3]
I/O	P116	P133	R20	P18	547 [3]
I/O	P117	P134	P18	P16	550 [3]
GND	P118	P135	GND[4]	GND[4]	-
I/O	-	P136	P20	P19	553 [3]
I/O	-	P137	N18	N17	556 [3]
I/O	P119	P138	N19	N18	559 [3]
I/O	P120	P139	N20	N19	562 [3]
VCC	P121	P140	VCC[4]	VCC[4]	-
I/O (D5[2])	P122	P141	M17	M19	565 [3]
I/O	P123	P142	M18	M17	568 [3]

XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280[2,5]	Bndry Scan
I/O	-	-	-	M18	571 [3]
I/O	-	-	M19	M16	574 [3]
I/O	P124	P144	M20	L19	577 [3]
I/O	P125	P145	L19	L18	580 [3]
I/O	P126	P146	L18	L17	583 [3]
I/O	P127	P147	L20	L16	586 [3]
I/O (D4[2])	P128	P148	K20	K19	589 [3]
I/O	P129	P149	K19	K18	592 [3]
VCC	P130	P150	VCC[4]	VCC[4]	-
GND	P131	P151	GND[4]	GND[4]	-
I/O (D3[2])	P132	P152	K18	K16	595 [3]
I/O	P133	P153	K17	K15	598 [3]
I/O	P134	P154	J20	J19	601 [3]
I/O	P135	P155	J19	J18	604 [3]
I/O	P136	P156	J18	J17	607 [3]
I/O	P137	P157	J17	J16	610 [3]
I/O	-	-	H20	H19	613 [3]
I/O	-	-	-	H18	616 [3]
I/O (D2[2])	P138	P159	H19	H17	619 [3]
I/O	P139	P160	H18	H16	622 [3]
VCC	P140	P161	VCC[4]	VCC[4]	-
I/O	P141	P162	G19	G18	625 [3]
I/O	P142	P163	F20	G17	628 [3]
I/O	-	P164	G18	G16	631 [3]
I/O	-	P165	F19	F19	634 [3]
GND	P143	P166	GND[4]	GND[4]	-
I/O	-	P167	F18	F18	637 [3]
I/O	P144	P168	E19	F17	640 [3]
I/O	P145	P169	D20	F16	643 [3]
I/O	P146	P170	E18	F15	646 [3]
I/O	P147	P171	D19	E19	649 [3]
I/O	P148	P172	C20	E17	652 [3]
I/O (D1[2])	P149	P173	E17	E16	655 [3]
I/O	P150	P174	D18	D19	658 [3]
I/O	-	-	-	D18	661 [3]
I/O	-	-	-	D17	664 [3]
I/O	P151	P175	C19	C19	667 [3]
I/O	P152	P176	B20	B19	670 [3]
I/O (D0[2], DIN)	P153	P177	C18	C18	673 [3]
I/O, SGCK4[1], GCK6[2] (DOUT)	P154	P178	B19	B18	676 [3]
CCLK	P155	P179	A20	A19	-
VCC	P156	P180	VCC[4]	VCC[4]	-